Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination		
09/955,146	TERASAKI, HIROSHI		
Examiner	Art Unit		
Ashutosh Upreti	2623		

SEARCHED					
Class	Subclass	Date	Examiner		
382	100, 298, 299, 240, 302, 305, 232	09/29/04	A.4.		
709	203	9/29/64	A.U.		
705 713	57	9/29/04	A·u.		
713	176	9/29/64	A.U.		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Talked to Jon Chang: Search: 382/100, 298,299 + IEEE (NPL)	9/29/04	Ач.		
Talked to Andy Johns: Search: 382/100,232 709,713/176 705	9/29/04	A.u.		
Talked to Wenpeng Chen Search: 382/240,302,305 709	9/29/04	A.u.		
STIC Searched NPL for waternark in lownes- olution a part of high resolution image	10/26/04	A.u.		
STIC searched for: output of high resolution data if watermark detected, else output of law resolution data	11/03/04	A·u.		
conducted search in EAST-see search history (including EPO, JPO, Derwent)	11/22/04	A·U.		
Searched IEEE Xplore for "watermark (and) resolution"	11/22/04	Ą.u.		